



Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0002

CB Certificate No.: JQAQ0002-001-T

Schedule Number: IECQ-L JQAJP 13.0002-S

Rev No.: 2

Revision Date:2014/01/24

Page 1 of 2

Type of Components

- QC 300000 (Fixed capacitor)
- QC 400000 (Fixed register)
- QC 230000 (Printed circuit board)
- QC 700000 (Semiconductor Devices)

ENVIRONMENTAL TEST

- IEC 60068-2-1 (Test A: Cold)
- IEC 60068-2-2 (Test B: Dry heat)
- IEC 60068-2-11 (Test Ka: Salt mist)
- IEC 60068-2-14 (Test N: Change of temperature)
- IEC 60068-2-20 (Test T: Test methods for solderability and resistance to soldering heat of devices with leads)
- IEC 60068-2-30 (Test Db: Damp heat, cyclic (12+12-hour cycle))
- IEC 60068-2-38 (Test Z/AD: Composite temperature/humidity cyclic test)
- IEC 60068-2-42 (Test Kc: Sulphur dioxide test for contacts and connections)
- IEC 60068-2-43 (Test Kd: Hydrogen sulphide test for contacts and connections)
- IEC 60068-2-45 (Test XA and guidance: Immersion in cleaning solvents)
- IEC 60068-2-52 (Test Kb: Salt mist, cyclic (sodium chloride solution))
- IEC 60068-2-54 (Test Ta: Soldering. Solderability testing by the wetting balance method)
- IEC 60068-2-58 (Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD))
- IEC 60068-2-60 (Test Ke: Flowing mixed gas corrosion test)
- IEC 60068-2-66 (Test Cx: Damp heat, steady state (unsaturated pressurized vapour))
- IEC 60068-2-78 (Test Cab: Damp heat, steady state)
- JIS C 60068-2-53 (Tests and Guidance: Combined climatic (temperature/humidity and dynamic (vibration/shock) tests)

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. www.iecq.org





Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0002

CB Certificate No.: JQAQ0002-001-T

Schedule Number: IECQ-L JQAJP 13.0002-S

Rev No.: 2

Revision Date:2014/01/24

Page 2 of 2

MECHANICAL TEST

IEC 60068-2-6 (Test Fc: Vibration (sinusoidal))

IEC 60068-2-21 (Test U: Robustness of terminations and integral mounting devices)

IEC 60068-2-27 (Test Ea and guidance: Shock)

IEC 60068-2-31 (Test Ec: Rough handling shocks, primarily for equipment-type specimens)

STRESS TEST

EIAJ ED-4701 Test Method 304 (Human Body Model Electrostatic Discharge (HBM/ESD))

EIAJ ED-4701 Test Method 305 (Charged Device Model Electrostatic Discharge (CDM/ESD))

EIAJ ED-4701 Test Method 306 (Latch-Up)

LED OPTICAL CHARACTERISTIC TEST

JIS C 7801 (Measuring methods of lamps for general lighting)

JIS C 8152-1 (Photometry of white light emitting diode for general lighting- Part 1: LED packages)

JIS C 8152-2 (Photometry of white light emitting diode for general lighting- Part 2: LED modules and LED light engines)

JIS C 8105-5 (Luminaires-Part 5: Gonio-photometric method)

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. www.iecq.org

